

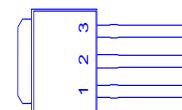
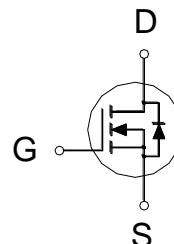
**NIKO-SEM****N-Channel Enhancement Mode  
Field Effect Transistor****P8010BIS**

TO-251(IS)

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
100V	85mΩ	15A



1. GATE
2. DRAIN
3. SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNITS
Drain-Source Voltage		$V_{DS}$	100		V
Gate-Source Voltage		$V_{GS}$	$\pm 20$		V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	$I_D$	15		A
	$T_C = 100^\circ\text{C}$		9		
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	35		
Avalanche Current		$I_{AS}$	12		
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	7.2		mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	$P_D$	46		W
	$T_C = 100^\circ\text{C}$		18		
Junction & Storage Temperature Range		$T_J, T_{stg}$	-55 to 150		°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2.7	°C / W

<sup>1</sup>Pulse width limited by maximum junction temperature.

**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	Typ	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.8	2.3	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}$			1	
		$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	μA
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = 5\text{V}, V_{GS} = 10\text{V}$	35			A
Drain-Source On-State Resistance <sub>1</sub>	$R_{DS(\text{ON})}$	$V_{GS} = 4.5\text{V}, I_D = 10\text{A}$		67	95	
		$V_{GS} = 10\text{V}, I_D = 15\text{A}$		61	85	mΩ
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 5\text{V}, I_D = 15\text{A}$		25		S

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DYNAMIC						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		527		pF
Output Capacitance	$C_{oss}$			68		
Reverse Transfer Capacitance	$C_{rss}$			37		
Gate Resistance	$R_g$	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		1.5		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{GS} = 10V, V_{DS} = 0.5V_{(BR)DSS}, I_D = 15A$		18.5		nC
Gate-Source Charge <sup>2</sup>	$Q_{gs}$			2.7		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			5.1		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$			11		
Rise Time <sup>2</sup>	$t_r$	$V_{DS} = 40V$ $I_D \approx 15A, V_{GS} = 10V, R_{GEN} = 6\Omega$		48		nS
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$			80		
Fall Time <sup>2</sup>	$t_f$			73		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_J = 25^\circ C$ )						
Continuous Current	$I_S$				15	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 15A, V_{GS} = 0V$			1.1	V
Reverse Recovery Time	$t_{rr}$	$I_F = 15A, dI_F/dt = 100A/\mu S$		33		nS
Reverse Recovery Charge	$Q_{rr}$			35		nC

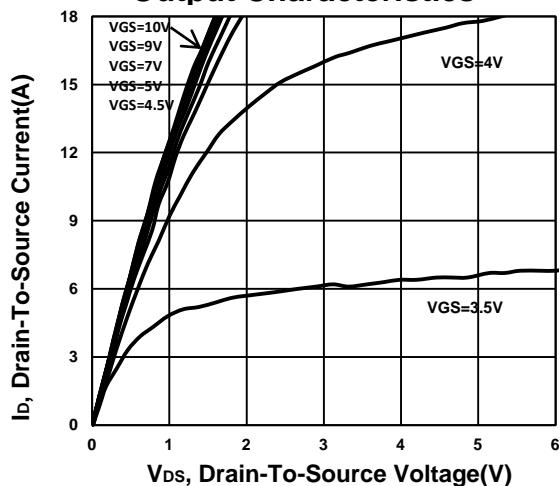
<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

**NIKO-SEM**

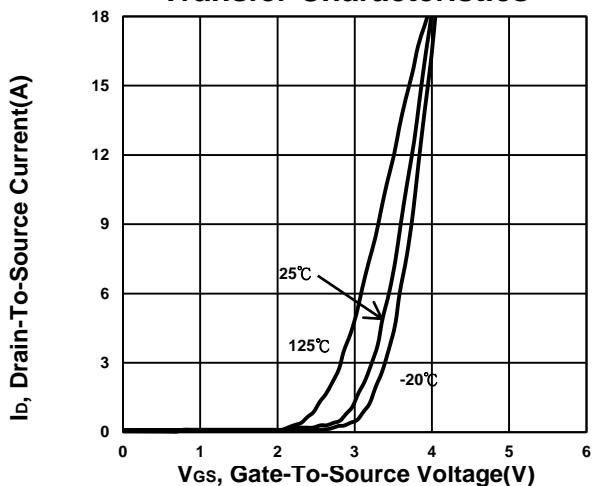
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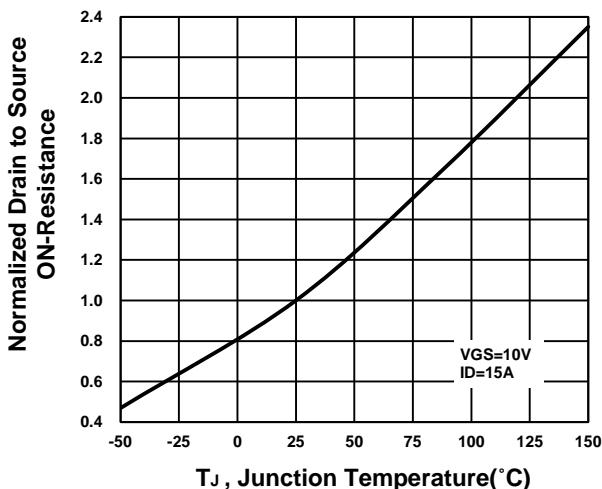
**Output Characteristics**



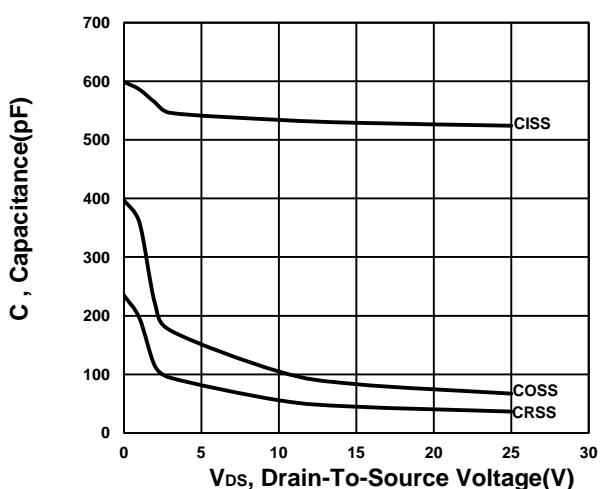
**Transfer Characteristics**



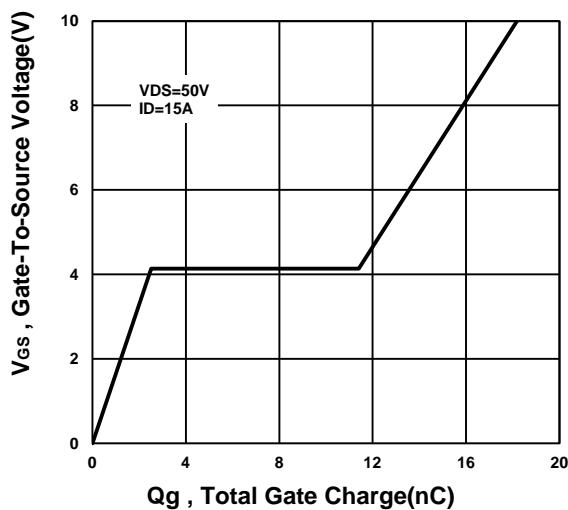
**On-Resistance VS Temperature**



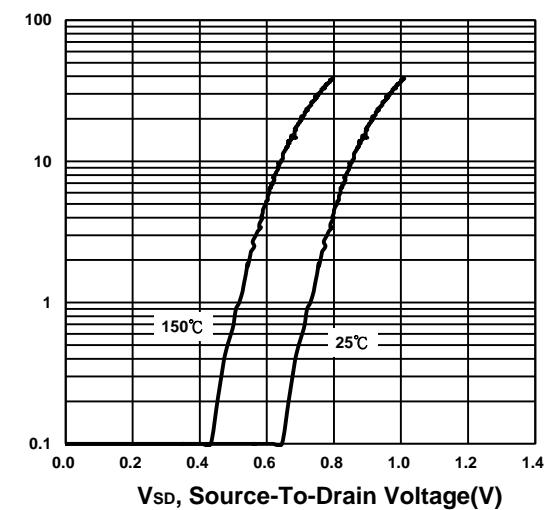
**Capacitance Characteristic**



**Gate charge Characteristics**



**Source-Drain Diode Forward Voltage**

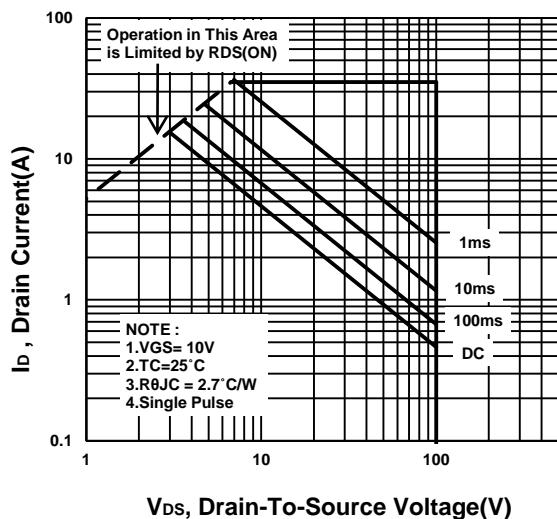


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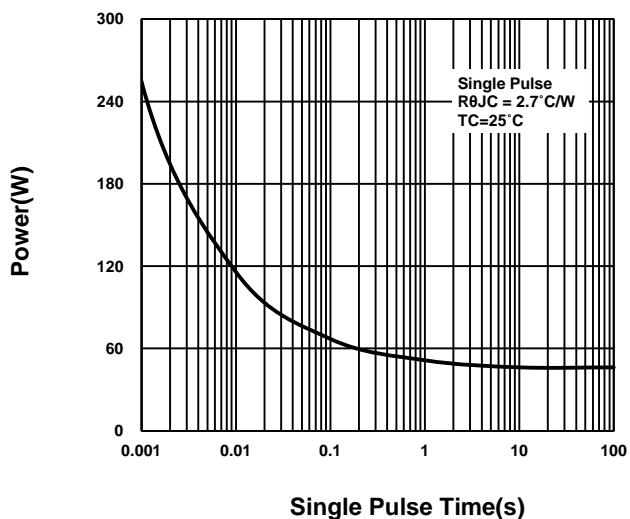
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**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**

